

N-Channel Silicon Carbide MOSFET Module

Rev.01 - 5 February 2024

Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and PressFit pin type. Intergrated with NTC temperature sensor.



2. Features and benefits

- Half bridge topology
- PressFit pins technology
- Low R_{DSon}
- Low Switching Losses
- Low Q_g and C_{rss}
- Low Inductive Design

3. Applications

- Power inverters
- AC-DC converters
- DC-DC converters
- Active power factor correctors
- Motor drivers

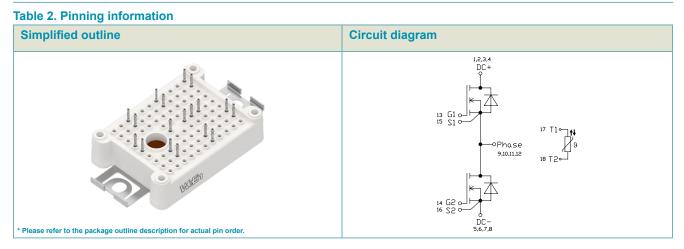
4. Quick reference data

Table 1 Quick reference data

Table 1. Q	uick reference data						
Symbol	Parameter	Conditions	Notes	Values			Unit
Absolute	maximum rating						
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			70		А
P _{tot}	total power dissipation	T _h = 25 °C			118		W
Tj	junction temperature			-40 to 150			°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 50 A; T _j = 25 °C		-	20	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 50 A; T _j = 25 °C		-	15.9	-	mΩ
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	232	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	44	-	nC
Source-d	rain diode						
Q _r	recovered charge	I_{SD} = 50 A; V _{GS} = -4 V; di/dt = 8500 A/µs; V _R = 600 V; T _j = 25 °C		-	810	-	nC

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5. Pinning information



6. Ordering information

Table 3. Ordering information									
Type number	Package Name	Orderable part number	Packing method	Small packing quantity		Package issue date			
WMSC020H12B1P	WeEnPACK-B1	WMSC020H12B1P6T	Tray	16	WeEnPACK- B1PHB-A	14-Dec-2023			

7. Marking

Table 4. Marking codes								
Type number	Marking codes							
WMSC020H12B1P	WMSC020H12B1P							

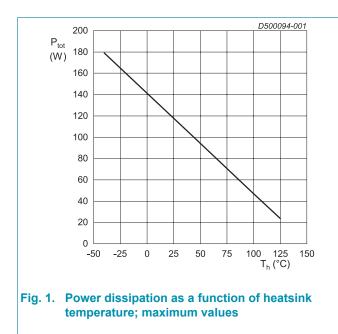
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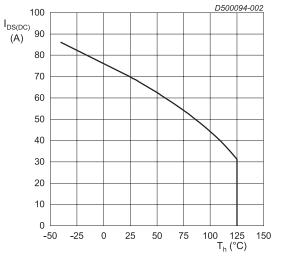
8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T _{stg}	storage temperature			-40 to 150	°C
T _{j.op}	operating junction temperature			-40 to 150	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET	-				
V _{DS}	drain-source voltage	T _j = 25 °C		1200	V
V _{GS,max}	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		118	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		70	А
		V _{GS} = 18 V; T _h = 100 °C		44	А
I _{DM}	peak drain current	pulse width t_p limited by T_{jmax}	Fig.17	140	А
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 24 A; L = 1 mH; V _{DD} = 100 V; T _{j(init)} = 25 °C; per MOSFET		288	mJ
Body Diod	de	·	· · ·		
I _{SD}	DC body diode forward current	V _{GS} = -4 V; T _h = 25 °C		28	А
I _{SD,pulse}	Pulse body diode current	verified by design, t_p limited by T_{jmax}		140	А





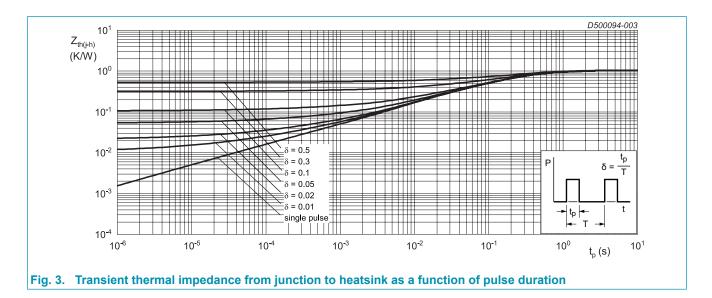


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9. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.38	-	K/W
$R_{th(j-h)}$	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 1 \text{ W/(m·K)}$		-	1.06	-	K/W
Internal l	solation	basic insulation (class 1, IEC 61140)		AI2O3			
d_{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d_{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index			>200			
F	Mounting force per clamp			20	-	50	Ν
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommanded.



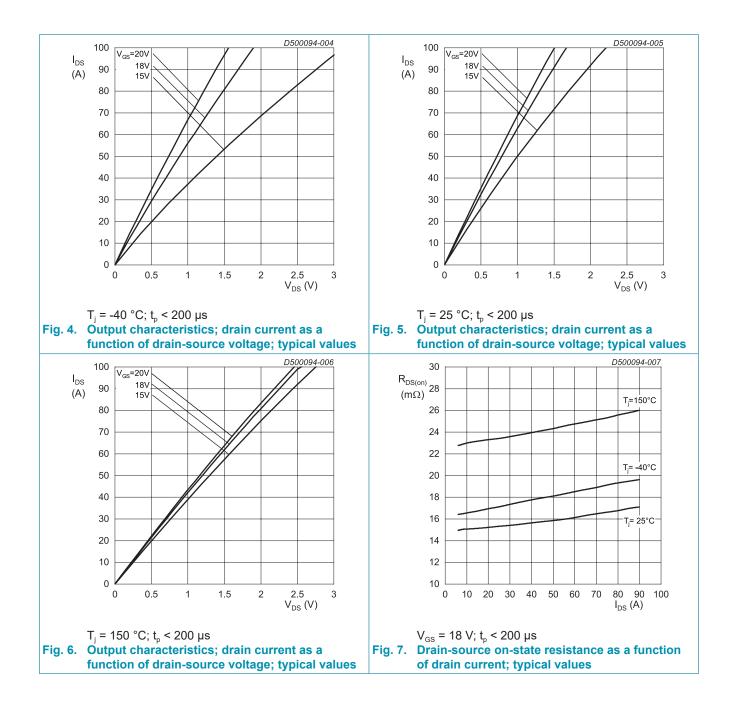
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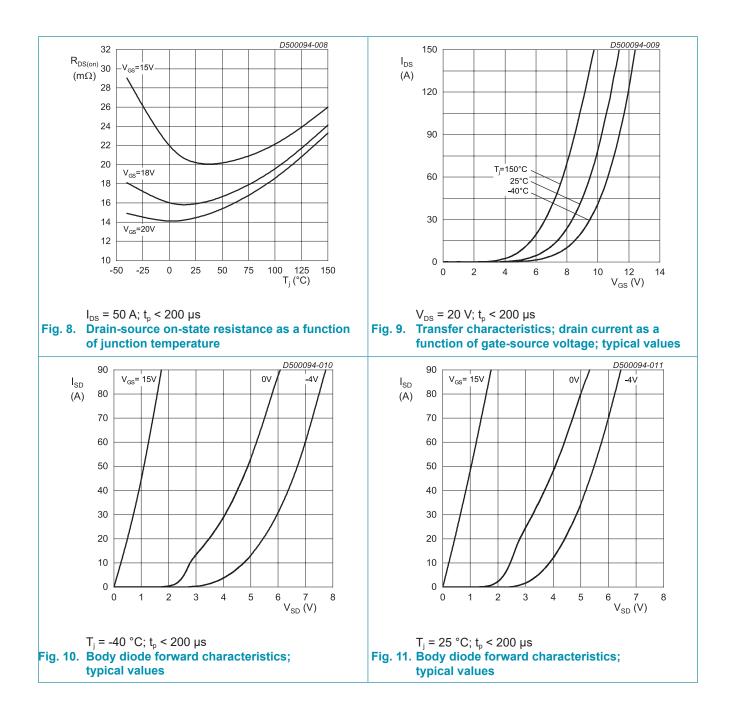
10. Characteristics

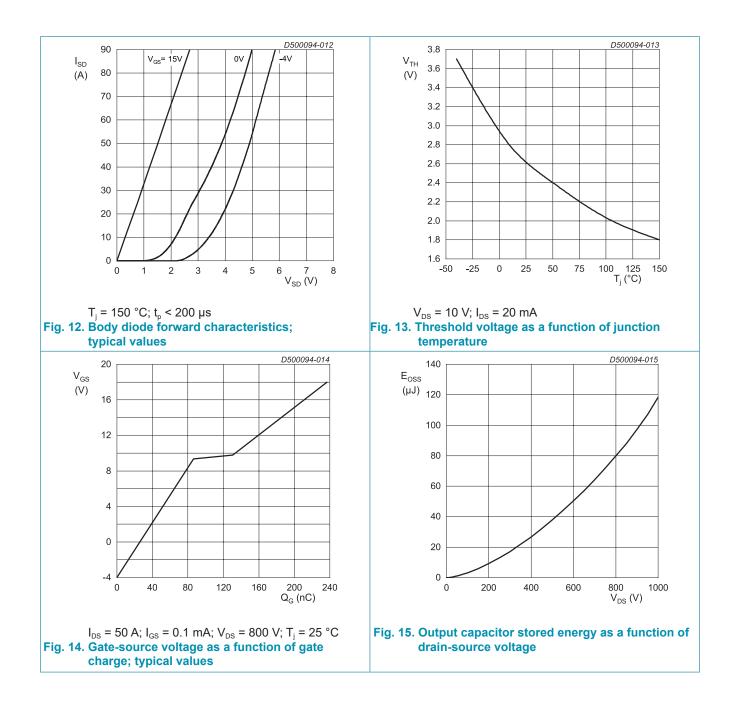
Table 7. Characteristics

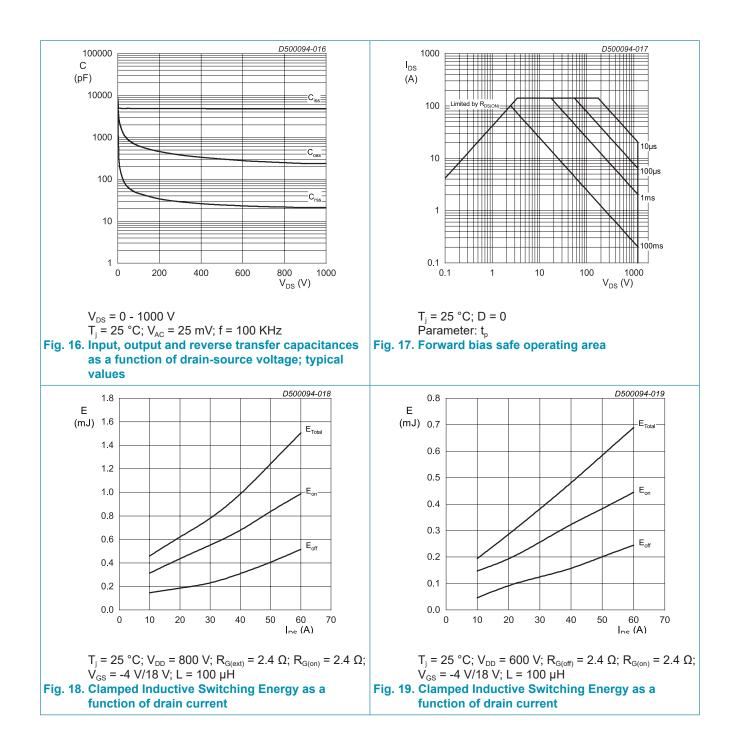
MOSFET							
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
V _{(BR)DSS}	drain-source breakdown voltage	I_{D} = 200 µA; V_{GS} = 0 V; T_{j} = 25 °C		1200	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_{D} = 20 mA; V_{DS} = 10 V; T_{j} = 25 °C		1.9	2.5	3.5	V
I _{DSS}	drain leakage current	V_{DS} = 1200 V; V_{GS} = 0 V; T_j = 25 °C		-	0.4	200	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	20	200	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	20	200	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 50 A; T _j = 25 °C		-	20	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 50 A; T _j = 25 °C		-	15.9	-	mΩ
		V _{GS} = 18 V; I _D = 50 A; T _j = 125 °C		-	21.7	-	mΩ
		V _{GS} = 18 V; I _D = 50 A; T _j = 150 °C		-	24.1	-	mΩ
R _G	gate resistance, each side	f = 1 MHz; T _j = 25 °C, each die with 4.7 Ω R _{G(ext)} in series		-	2.9	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 50 A; T _j = 25 °C		-	35	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_{\rm D}$ = 50 A; $V_{\rm DS}$ = 800 V; $V_{\rm GS}$ = -4 V/18 V;		-	232	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	86	-	nC
Q _{GD}	gate-drain charge			-	44	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 100 KHz;		-	4.8	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	237	-	pF
C _{rss}	reverse transfer capacitance			-	21.3	-	pF
E _{oss}	Coss stored energy			-	118	-	μJ
t _{d(on)}	turn-on delay time	$V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	22	-	ns
t _r	rise time	$R_{G(ext)} = 2.4 \Omega$; I _D = 50 A; L = 100 μH; T _i = 25 °C		-	42	-	ns
t _{d(off)}	turn-off delay time			-	68	-	ns
t _f	fall time			-	39	-	ns
Eon	turn-on energy			-	0.84	-	mJ
E _{off}	turn-off energy	1		-	0.4	-	mJ

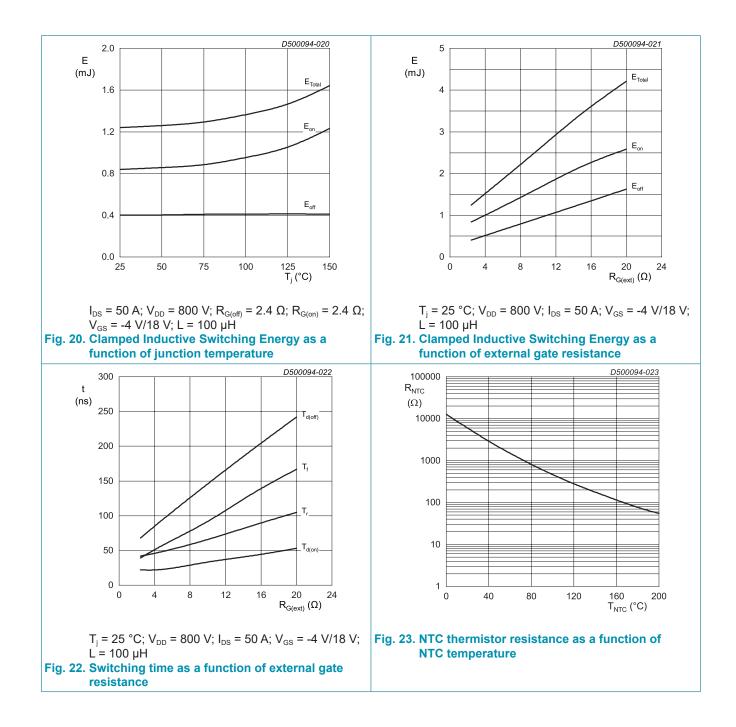
Body did	de						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics	·					
V_{SD}	source-drain voltage	V_{GS} = -4 V; I_{SD} = 50 A; T_{j} = 25 °C		-	5.5	-	V
		V _{GS} = -4 V; I _{SD} = 50 A; T _j = 150 °C		-	4.9	-	V
Dynamic	characteristics						
t _{rr}	reverse recovery time	I_{SD} = 50 A; V_{GS} = -4 V; di/dt = 8500 A/µs;		-	19	-	ns
Q _r	recovered charge	V _R = 600 V; T _j = 25 °C		-	810	-	nC
I _{rrm}	reverse recovery current			-	71	-	А
E _{rec}	reverse recovery energy			-	345	-	μJ
t _{rr}	reverse recovery time	I_{SD} = 50 A; V_{GS} = -4 V; di/dt = 11000 A/µs;		-	22	-	ns
Q _r	recovered charge	V _R = 600 V; T _j = 150 °C		-	1670	-	nC
I _{rrm}	reverse recovery current			-	120	-	А
E _{rec}	reverse recovery energy			-	1135	-	μJ
NTC the	mistor					1	
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C		465±5%		Ω	
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380			К
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	s





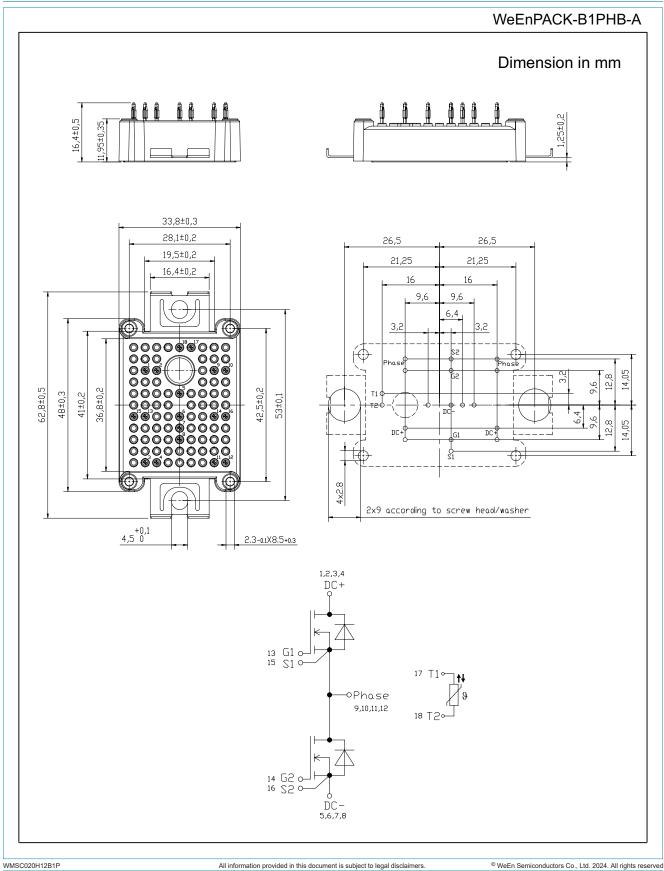






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11. Package outline



Product data sheet

N-Channel Silicon Carbide MOSFET Module

12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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